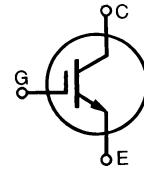
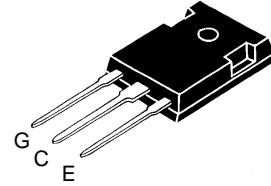


**Low $V_{CE(sat)}$
High speed IGBT**
**IXGH 25 N120
IXGH 25 N120A**

V_{CES}	I_{C25}	$V_{CE(sat)}$
1200 V	50 A	3 V
1200 V	50 A	4 V



Symbol	Test Conditions	Maximum Ratings		
V_{CES}	$T_J = 25^\circ\text{C}$ to 150°C	1200	V	
V_{GCR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GE} = 1 \text{ M}\Omega$	1200	V	
V_{GES}	Continuous	± 20	V	
V_{GEM}	Transient	± 30	V	
I_{C25}	$T_c = 25^\circ\text{C}$	50	A	
I_{C90}	$T_c = 90^\circ\text{C}$	25	A	
I_{CM}	$T_c = 25^\circ\text{C}, 1 \text{ ms}$	100	A	
SSOA (RBSOA)	$V_{GE} = 15 \text{ V}$, $T_{VJ} = 125^\circ\text{C}$, $R_G = 33 \Omega$ Clamped inductive load, $L = 100 \mu\text{H}$	$I_{CM} = 50$ @ 0.8 V_{CES}	A	
P_c	$T_c = 25^\circ\text{C}$	200	W	
T_J		-55 ... +150	$^\circ\text{C}$	
T_{JM}		150	$^\circ\text{C}$	
T_{stg}		-55 ... +150	$^\circ\text{C}$	
M_d	Mounting torque (M3)	1.13/10	Nm/lb.in.	
Weight		6	g	
Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s		300	$^\circ\text{C}$	

TO-247 AD

G = Gate,
C = Collector,
E = Emitter,
TAB = Collector

Features

- International standard package JEDEC TO-247 AD
- 2nd generation HDMOS™ process
- Low $V_{CE(sat)}$
 - for low on-state conduction losses
- MOS Gate turn-on
 - drive simplicity

Applications

- AC motor speed control
- DC servo and robot drives
- DC choppers
- Uninterruptible power supplies (UPS)
- Switch-mode and resonant-mode power supplies
- Capacitor discharge systems
- Solid state relays

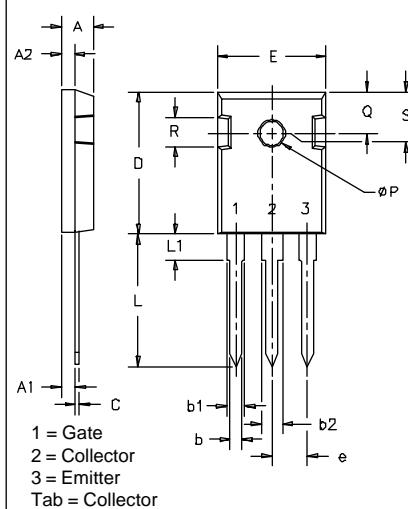
Advantages

- Easy to mount with 1 screw (TO-247)
(isolated mounting screw hole)
- High power density

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
BV_{CES}	$I_C = 3 \text{ mA}$, $V_{GE} = 0 \text{ V}$	1200		V
$V_{GE(th)}$	$I_C = 250 \mu\text{A}$, $V_{CE} = V_{GE}$	2.5	6	V
I_{CES}	$V_{CE} = 0.8 \cdot V_{CES}$ $V_{GE} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$	250 1	μA mA
I_{GES}	$V_{CE} = 0 \text{ V}$, $V_{GE} = \pm 20 \text{ V}$		± 100	nA
$V_{CE(sat)}$	$I_C = I_{C90}$, $V_{GE} = 15 \text{ V}$	25N120 25N120A	3 4	V

Symbol	Test Conditions	Characteristic Values			
		(T _j = 25°C, unless otherwise specified)	min.	typ.	max.
g_{fs}	I _C = I _{C90} ; V _{CE} = 10 V, Pulse test, t ≤ 300 μs, duty cycle ≤ 2 %	8	15	S	
C_{ies}	{ V _{CE} = 25 V, V _{GE} = 0 V, f = 1 MHz	2750		pF	
C_{oes}		200		pF	
C_{res}		50		pF	
Q_g	{ I _C = I _{C90} , V _{GE} = 15 V, V _{CE} = 0.5 V _{CES}	130	180	nC	
Q_{ge}		25	50	nC	
Q_{gc}		55	90	nC	
t_{d(on)}	{ Inductive load, T _j = 25°C I _C = I _{C90} , V _{GE} = 15 V, L = 100 μH, V _{CE} = 0.8 V _{CES} , R _G = R _{off} = 33 Ω Remarks: Switching times may increase for V _{CE} (Clamp) > 0.8 • V _{CES} , higher T _j or increased R _G	100		ns	
t_r		250		ns	
t_{d(off)}		650	1000	ns	
t_f		700		ns	25N120
E_{off}		600	800	ns	25N120A
t_{d(on)}	{ Inductive load, T _j = 125°C I _C = I _{C90} , V _{GE} = 15 V, L = 100 μH, V _{CE} = 0.8 V _{CES} , R _G = R _{off} = 33 Ω Remarks: Switching times may increase for V _{CE} (Clamp) > 0.8 • V _{CES} , higher T _j or increased R _G	100		ns	
t_r		250		ns	
E_{on}		4.2		mJ	
t_{d(off)}		720	1000	ns	25N120
t_f		1200		ns	25N120A
E_{off}		800	1200	ns	25N120A
R_{thJC}		15		mJ	
R_{thCK}		0.25		K/W	
				0.62 K/W	

TO-247 AD Outline



SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.185	.209	4.7	5.3
A ₁	.087	.102	2.2	2.54
A ₂	.059	.098	2.2	2.6
b	.040	.055	1.0	1.4
b ₁	.065	.084	1.65	2.13
b ₂	.113	.123	2.87	3.12
C	.016	.031	.4	.8
D	.819	.845	20.80	21.46
E	.610	.640	15.75	16.26
e	.215	BSC	5.45	BSC
L	.780	.800	19.81	20.32
L ₁		.177		4.50
ØP	.140	.144	3.55	3.65
Q	.212	.244	5.4	6.2
R	.170	.216	4.32	5.49
S	.242	BSC	6.15	BSC

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715
4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025